Search Notes

	Applicant(s)/Patent R examination
10/702 225	MICHIE TAKELID

10/723,225

Examiner

Matthew J. Kasztejna

Applicant(s)/Patent under
R examination
NISHIIE, TAKEHIRO
Art Unit
3739

SEARCHED				
Class	Subclass	Date	Examiner	
updated	all	5/26/2006	MJK	
		*		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
		•••		
	<u> </u>			
	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	